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(54) **INTEGRATED SPECTROSCOPY SYSTEM**

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4,929,063 A * 5/1990 Durand et al. 359/241
4,989,216 A 1/1991 Chandra et al.
5,263,037 A 11/1993 Trutna, Jr. et al.
5,321,501 A 6/1994 Swanson et al.
5,430,574 A * 7/1995 Tehrani 359/378
5,434,943 A * 7/1995 Dentai et al. 385/129
5,459,570 A 10/1995 Swanson et al.
5,465,147 A 11/1995 Swanson

(Continued)

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FOREIGN PATENT DOCUMENTS

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DE 41 22 925 A1 1/1993
EP 0 501 559 A1 9/1992

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(Continued)

Related U.S. Patent Documents

OTHER PUBLICATIONS

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Gmachl et al. "Ultra-broadband semiconductor laser" Nature, Feb. 21, 2002, vol. 415, pp. 883-887.*

(Continued)

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See application file for complete search history.

(57)

ABSTRACT

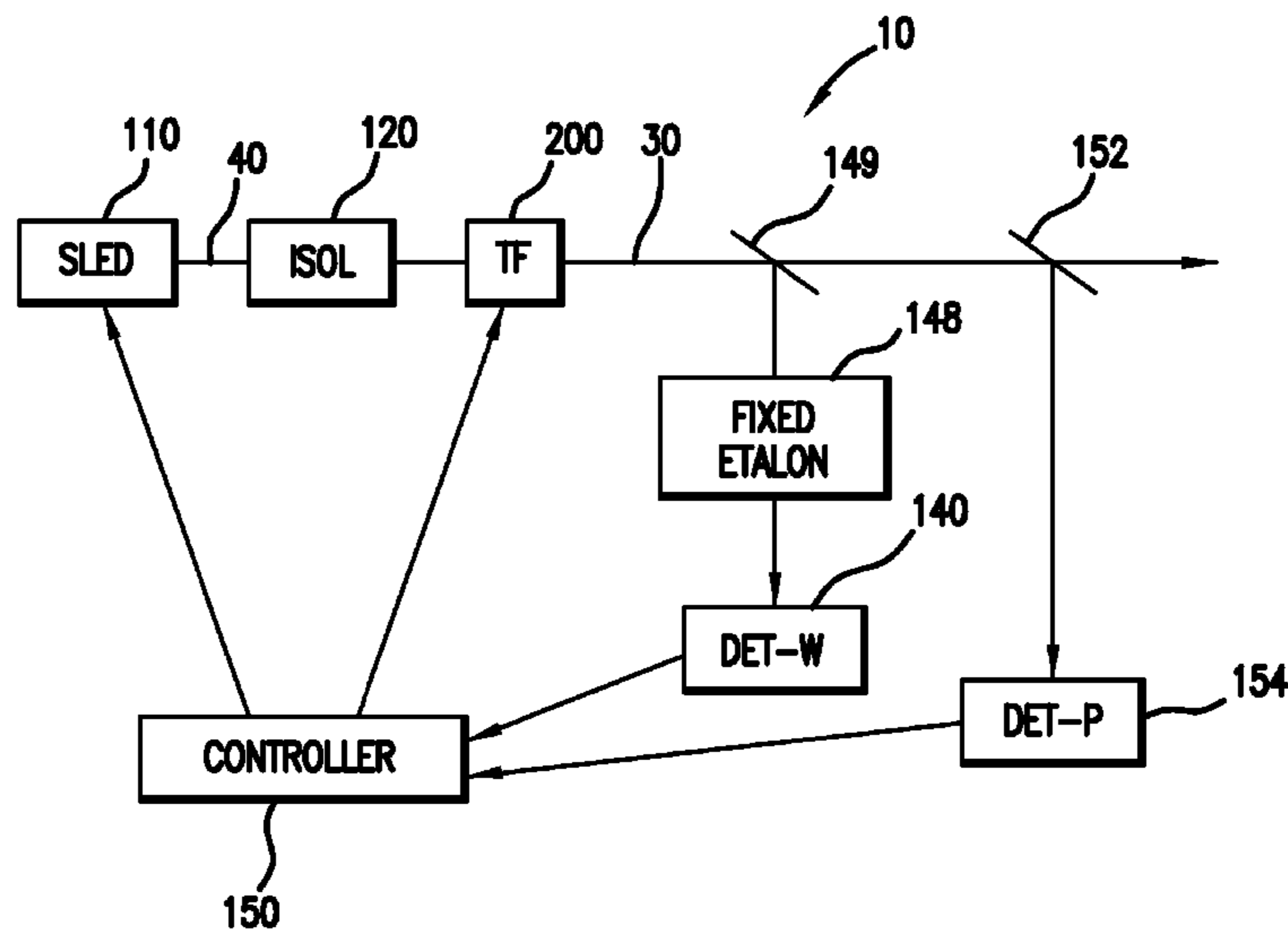
Integrated spectroscopy systems are disclosed. In some examples, integrated tunable detectors, using one or multiple Fabry-Perot tunable filters, are provided. Other examples use integrated tunable sources. The tunable source combines one or multiple diodes, such as superluminescent light emitting diodes (SLED), and a Fabry Perot tunable filter or etalon. The advantages associated with the use of the tunable etalon are that it can be small, relatively low power consumption device. For example, newer microelectrical mechanical system (MEMS) implementations of these devices make them the size of a chip. This increases their robustness and also their performance. In some examples, an isolator, amplifier, and/or reference system is further provided integrated.

(56) **References Cited**

U.S. PATENT DOCUMENTS

3,914,055 A * 10/1975 Wolga et al. 356/454
4,466,699 A * 8/1984 Droessler et al. 359/578

18 Claims, 18 Drawing Sheets



(56)

References Cited

U.S. PATENT DOCUMENTS

5,475,221	A	12/1995	Wang	
5,500,762	A	3/1996	Uchiyama et al.	
5,509,093	A	4/1996	Miller et al.	
5,537,634	A *	7/1996	Fye	398/76
5,574,739	A	11/1996	Carruthers et al.	
5,600,466	A *	2/1997	Tsushima et al.	398/79
5,619,368	A	4/1997	Swanson	
5,627,668	A *	5/1997	Fye	398/76
5,646,729	A	7/1997	Koskinen et al.	
5,724,373	A	3/1998	Chang	
5,742,418	A *	4/1998	Mizutani et al.	398/184
5,748,598	A	5/1998	Swanson et al.	
5,784,352	A	7/1998	Swanson et al.	
5,808,788	A *	9/1998	Park et al.	359/341.4
5,818,586	A	10/1998	Lehto et al.	
5,956,355	A	9/1999	Swanson et al.	
5,991,477	A	11/1999	Ishikawa et al.	
6,111,645	A	8/2000	Tearney et al.	
6,134,003	A	10/2000	Tearney et al.	
6,160,826	A *	12/2000	Swanson et al.	372/20
6,191,862	B1	2/2001	Swanson et al.	
6,204,920	B1	3/2001	Ellerbrock et al.	
6,282,011	B1	8/2001	Tearney et al.	
6,282,215	B1	8/2001	Zorabedian et al.	
6,339,603	B1 *	1/2002	Flanders et al.	372/20
6,345,059	B1 *	2/2002	Flanders	372/20
6,357,913	B1 *	3/2002	Kim et al.	383/28
6,359,724	B1	3/2002	Katagiri et al.	
6,373,632	B1	4/2002	Flanders	
6,377,386	B1 *	4/2002	Korn	359/260
6,381,022	B1	4/2002	Zavracky	
6,407,376	B1 *	6/2002	Korn et al.	250/227.23
6,421,164	B2	7/2002	Tearney et al.	
6,445,939	B1	9/2002	Swanson et al.	
6,473,234	B2 *	10/2002	Kuznetsov	359/578
6,485,413	B1	11/2002	Boppart et al.	
6,490,074	B1 *	12/2002	Korn	359/260
6,501,551	B1	12/2002	Tearney et al.	
6,510,261	B2 *	1/2003	Sorin et al.	385/27
6,552,796	B2	4/2003	Magnin et al.	
6,564,087	B1	5/2003	Pitris et al.	
6,570,659	B2	5/2003	Schmitt	
6,608,711	B2	8/2003	Flanders et al.	
6,619,864	B2	9/2003	Johnson et al.	
6,639,666	B2	10/2003	Li	
6,706,004	B2	3/2004	Tearney et al.	
6,816,515	B1	11/2004	Yun et al.	
6,845,121	B2 *	1/2005	McDonald	372/34
6,853,654	B2 *	2/2005	McDonald et al.	372/20
6,862,136	B2 *	3/2005	Koren et al.	359/344
6,879,619	B1 *	4/2005	Green et al.	372/98
6,879,851	B2	4/2005	McNamara et al.	
6,888,856	B2 *	5/2005	Green et al.	372/20
6,891,984	B2	5/2005	Petersen et al.	
6,901,087	B1	5/2005	Richardson et al.	
6,905,255	B2 *	6/2005	Flanders et al.	385/88
6,999,491	B2	2/2006	Rieger et al.	
7,027,198	B2 *	4/2006	Yao	359/259
7,061,618	B2 *	6/2006	Atia et al.	356/454
7,075,058	B2	7/2006	Chinn et al.	
7,110,169	B1 *	9/2006	Walker et al.	359/344
7,120,176	B2 *	10/2006	McDonald et al.	372/29.02
7,157,712	B2 *	1/2007	Flanders et al.	250/339.07
7,208,333	B2	4/2007	Flanders et al.	
7,218,436	B2 *	5/2007	Yao	359/259
7,231,243	B2	6/2007	Tearney et al.	
7,241,286	B2	7/2007	Atlas	
7,242,509	B2 *	7/2007	Atia et al.	359/260
7,292,344	B2 *	11/2007	Atia et al.	356/454
7,349,631	B2 *	3/2008	Lee et al.	398/82
7,406,107	B2 *	7/2008	Flanders et al.	372/20
7,613,398	B2 *	11/2009	Lee et al.	398/82
7,625,366	B2	12/2009	Atlas	
2001/0013934	A1	8/2001	Varnham et al.	
2002/0054614	A1 *	5/2002	Jin	372/20

2002/0118459	A1 *	8/2002	Kuznetsov	359/578
2002/0161351	A1	10/2002	Samson et al.	
2003/0107745	A1	6/2003	Atia et al.	
2003/0179790	A1	9/2003	Bouda et al.	
2004/0151440	A1 *	8/2004	Flanders et al.	385/88
2005/0078716	A1	4/2005	Liu	
2005/0083533	A1 *	4/2005	Atia et al.	356/454
2005/0201662	A1	9/2005	Petersen et al.	
2006/0065834	A1 *	3/2006	Flanders et al.	250/339.07
2006/0072112	A1 *	4/2006	Flanders et al.	356/432
2006/0072632	A1 *	4/2006	Flanders et al.	372/20
2006/0187461	A1 *	8/2006	Atia et al.	356/454
2006/0263090	A1 *	11/2006	Lee et al.	398/79
2007/0081823	A1 *	4/2007	Lee et al.	398/79
2010/0076320	A1	3/2010	Petersen et al.	
2011/0051143	A1 *	3/2011	Flanders et al.	356/451

FOREIGN PATENT DOCUMENTS

EP	0524382	B1	1/1993
EP	0 709 659	A2	1/1996
EP	0 709 659	A2	5/1996
EP	0469259	B1	8/1996
EP	0911655	A2	4/1999
EP	1020969	B1	3/2007
FR	2704651	A1	11/1994
GB	2118768	A	11/1983
GB	2317045	A	3/1998
JP	63092917	A	4/1988
JP	8148744	A	6/1996
WO	2001065734	A2	9/2001
WO	03/046630	A1	6/2003
WO	2003096106	A1	11/2003

OTHER PUBLICATIONS

Brochure, "Agilent 83437A Broadband Light Source and Agilent 83438A Erbium ASE Source, Production Overview," Agilent Technologies, 1996, 2002.

Krawczyk, S. K. et al., "GaN and Related Compunds for MEMS and MOEMS," Aromagraph DC 2000 System, vol. 51, No. 8, 1999, pp. 623-625.

Vakhshoori, D. et al., "Raman Amplification Using High-Power Incoherent Semiconductor Pump Sources," Ahara Corporation, MA, 2003.

International Search Report, mailed Aug. 16, 2005, from counterpart International Application No. PCT/US2005/034691, filed on Oct. 13, 2004.

International Preliminary Report on Patentability, dated Apr. 18, 2006, from counterpart International Application No. PCT/US2005/034691, filed on Oct. 13, 2004.

Zhao, M., et al. "Analysis and Optimization of Intensity Noise Reduction in Spectrum-Sliced WDM Systems Using a Saturated Semiconductor Optical Amplifier," IEEE Photonics Technology Letters, vol. 14, No. 3, pp. 390-392, Mar. 2002.

Chang, T. et al., "Pulsed Dye-Laser with Grating and Etalon in a Symmetric Arrangement," Appl. Opt., vol. 19, No. 21, 1980, pp. 3651-3654.

Coquin, G. et al., "Single- and multiple-wavelength operation of acoustooptically tuned semiconductor lasers at 1.3 μm ," IEEE Journal of Quantum Electronics, vol. 25, No. 6, Jun. 1989, pp. 1575-1579.

Klauminzer, GK, "Etalon-Grating Synchronized Scanning of a Narrowband Pulsed Dye Laser," Optical Engineering, vol. 13, No. 6, 1974; pp. 528-530.

Kowalski, F.V. et al., "Optical pulse generation with a frequency shifted feedback laser," Applied Physics Letters, vol. 53, No. 9, Aug. 1988, pp. 734-736.

Oshiba, S. et al., "Tunable fiber ring lasers with an electronically accessible acousto-optic filter," Photonic Switching II, Proceedings of the International Topical Meeting, Kobe, Japan, Apr. 1990, pp. 241-244.

Shimizu, K. et al., "Measurement of Rayleigh Backscattering in Single-Mode Fibers Based on Coherent OFDR Employing a DFB Laser Diode," IEEE Photonics Technology Letters, vol. 3, No. 11, 1991, pp. 1039-1041.

(56)

References Cited

OTHER PUBLICATIONS

Takada, K. et al., "Loss distribution measurement of silica-based waveguides by using a jaggedness-free optical low coherence reflectometer," *Electronics Letters*, vol. 30, No. 17, Aug. 18, 1994, pp. 1441-1443.

Takada, K. et al., "Rapidly-tunable narrowband light source with symmetrical crossing configuration for low coherence reflectometry," *Electronics Letter*, Jan. 5, 1995, vol. 31, No. 1, pp. 63-65.

Takada, K. et al., "Tunable Narrow-Band Light Source Using Two Optical Circulators," *IEEE Photonics Technology Letters*, vol. 9, No. 1, 1997, pp. 91-93.

Telle, J.M. et al., "Very rapid tuning of cw dye laser," *Applied Physics Letters*, vol. 26, No. 10, 1975, pp. 572-574.

Yun, S.H. et al., "High-speed wavelength-swept semiconductor laser with a polygon-scanner-based wavelength filter," *Optics Letters*, vol. 28, No. 20, 2003, pp. 1981-1983.

Yun, S.H. et al., "Interrogation of fiber grating sensor arrays with a wavelength-swept fiber laser," *Optics Letters*, vol. 23, No. 11, 1998, pp. 843-845.

Yun, S.H. et al., "Wavelength-Swept Fiber Laser with Frequency Shifted Feedback and Resonantly Swept Intra-Cavity Acousto-Optic Tunable Filter," *IEEE Journal of Selected Topics in Quantum Electronics*, vol. 3, No. 4, 1997, pp. 1087-1096.

Bogatov, A. P. et al., "Anomalous Interaction of Spectral Modes in a Semiconductor Laser," *IEEE Journal of Quantum Electronics*, vol. QE-11, No. 7, Jul. 1975, pp. 510-515.

Fowles, G., "Introduction to Modern Optics," Dover, Second edition, 1975, pp. 85-91.

* cited by examiner

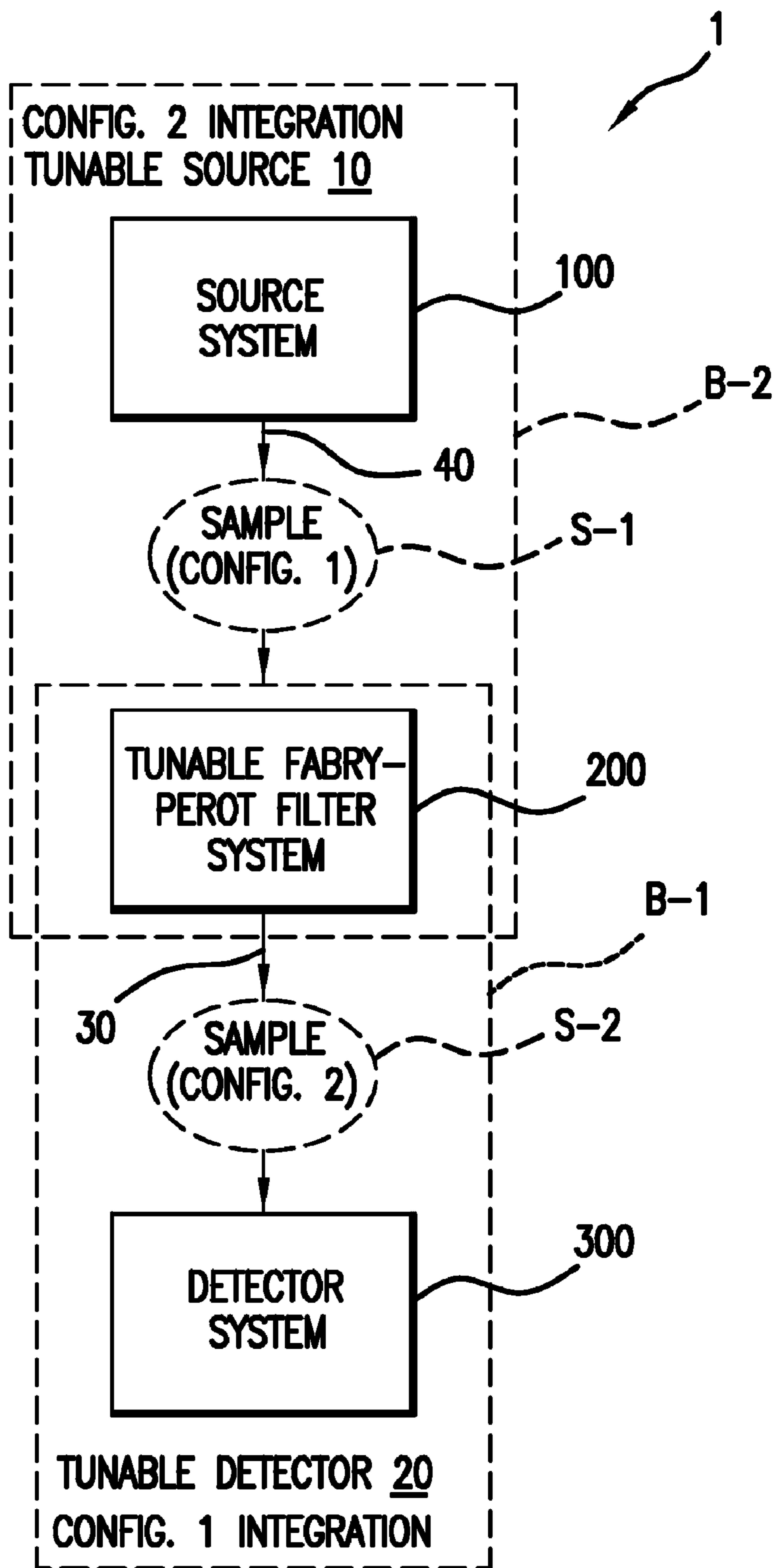


FIG. 1A

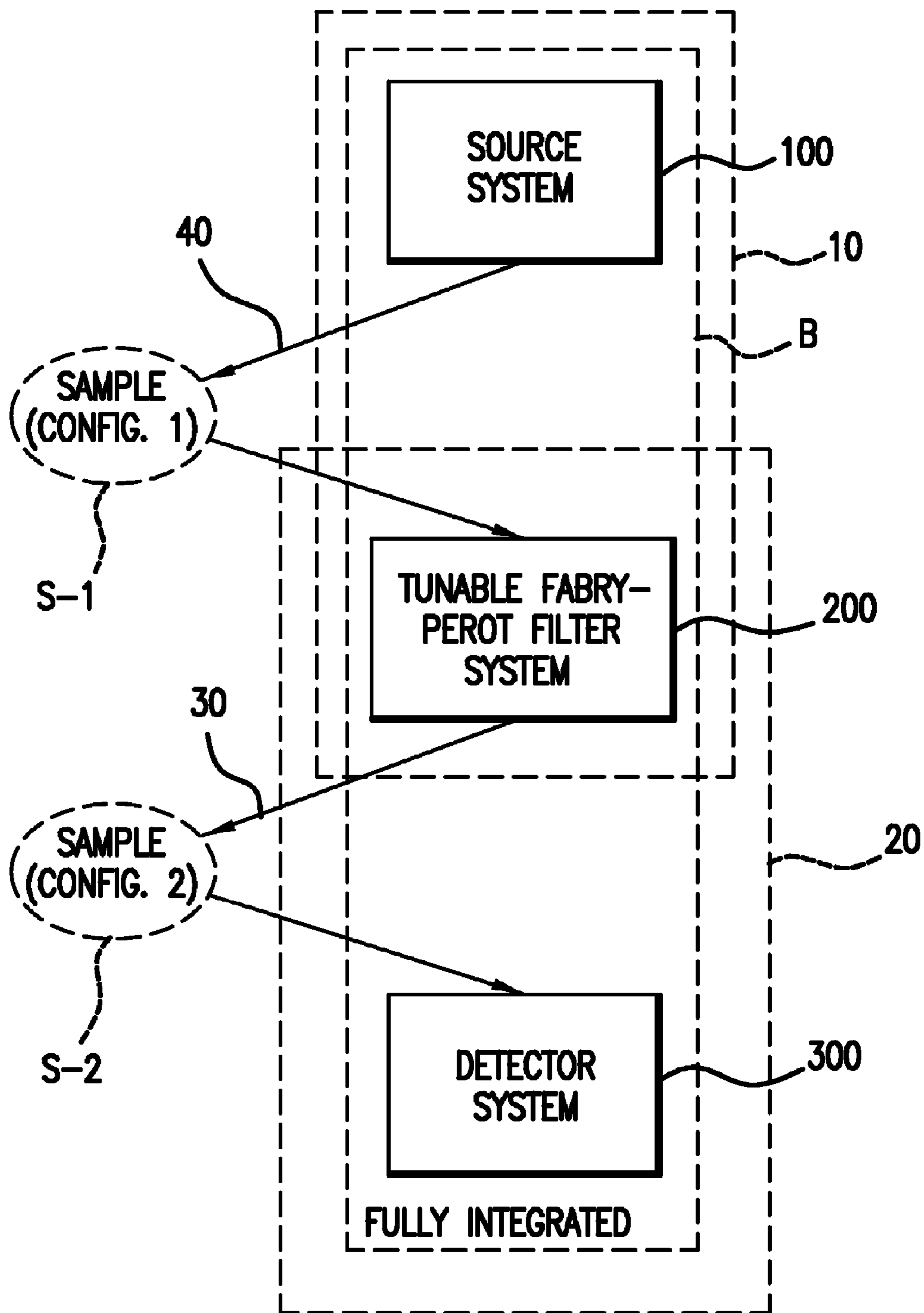


FIG. 1B

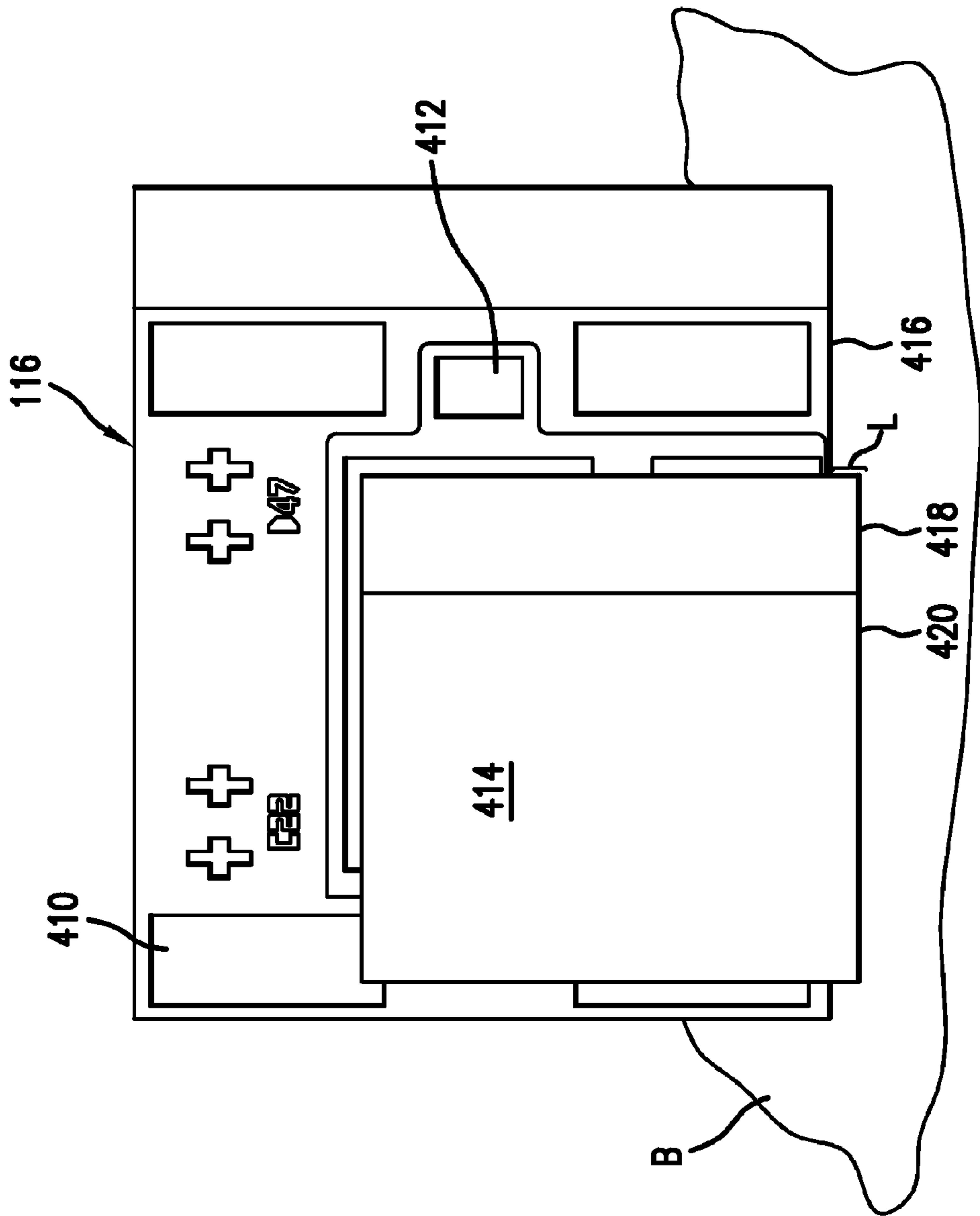


FIG. 3A

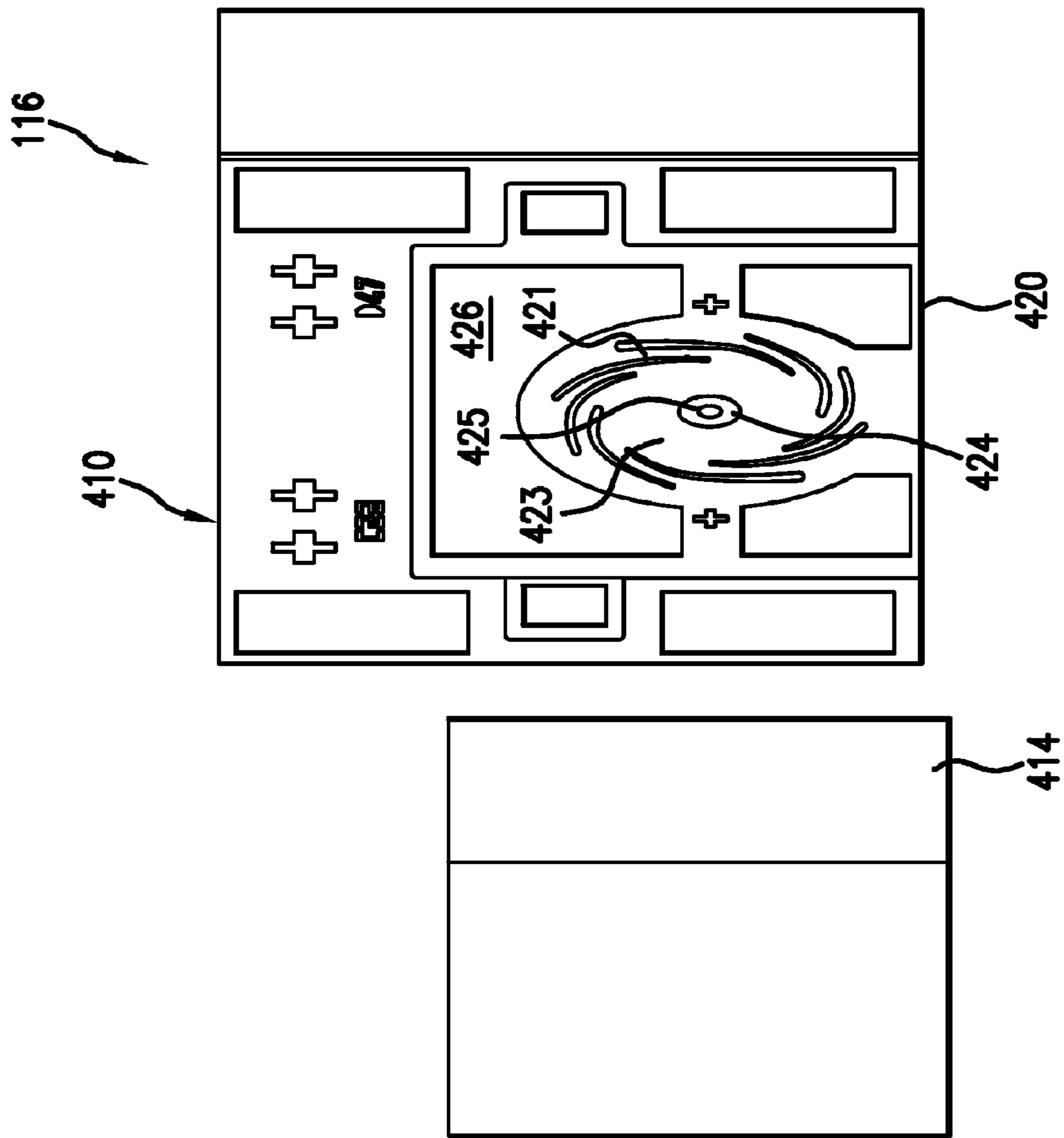


FIG. 3B

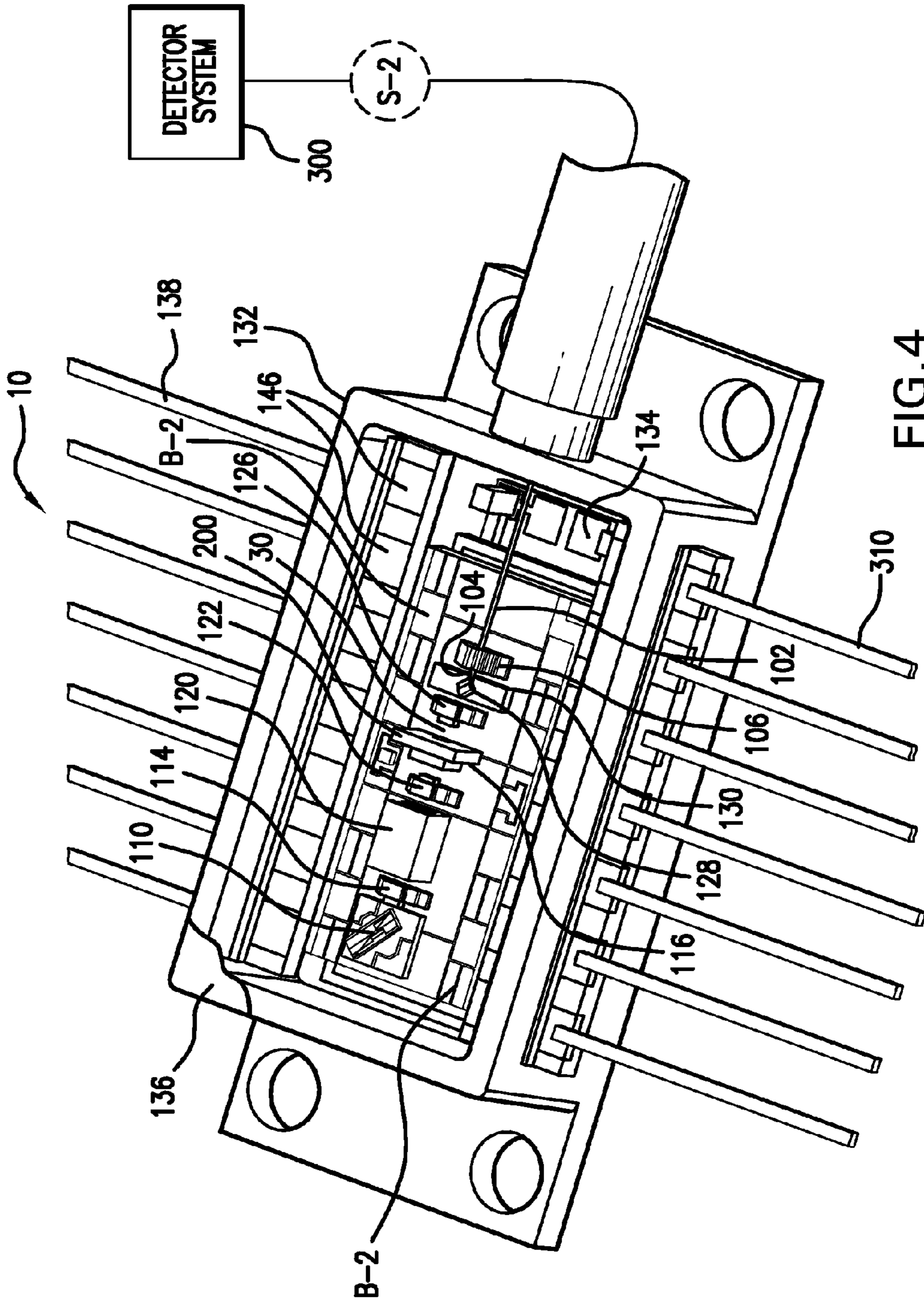


FIG. 4

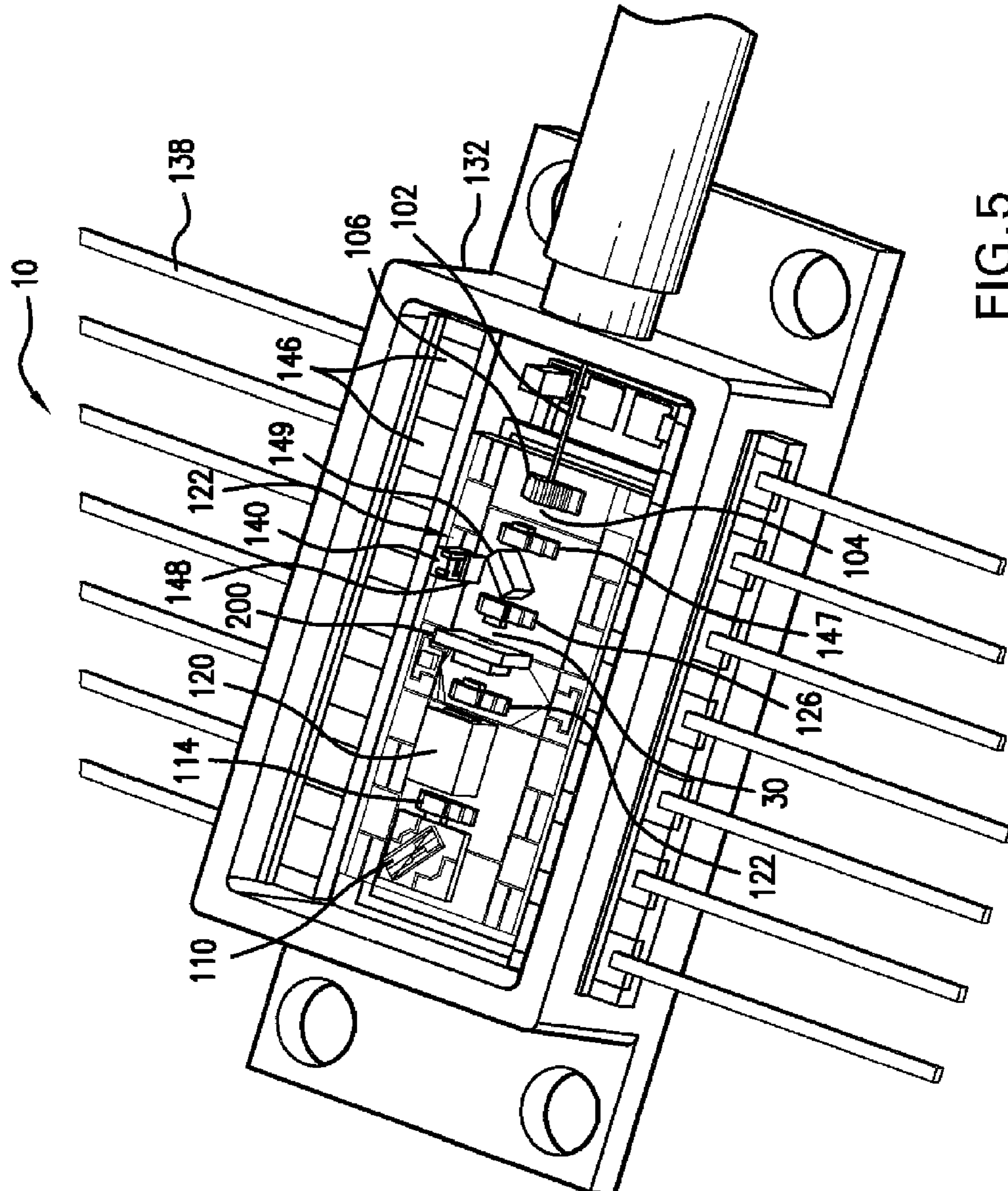


FIG. 5

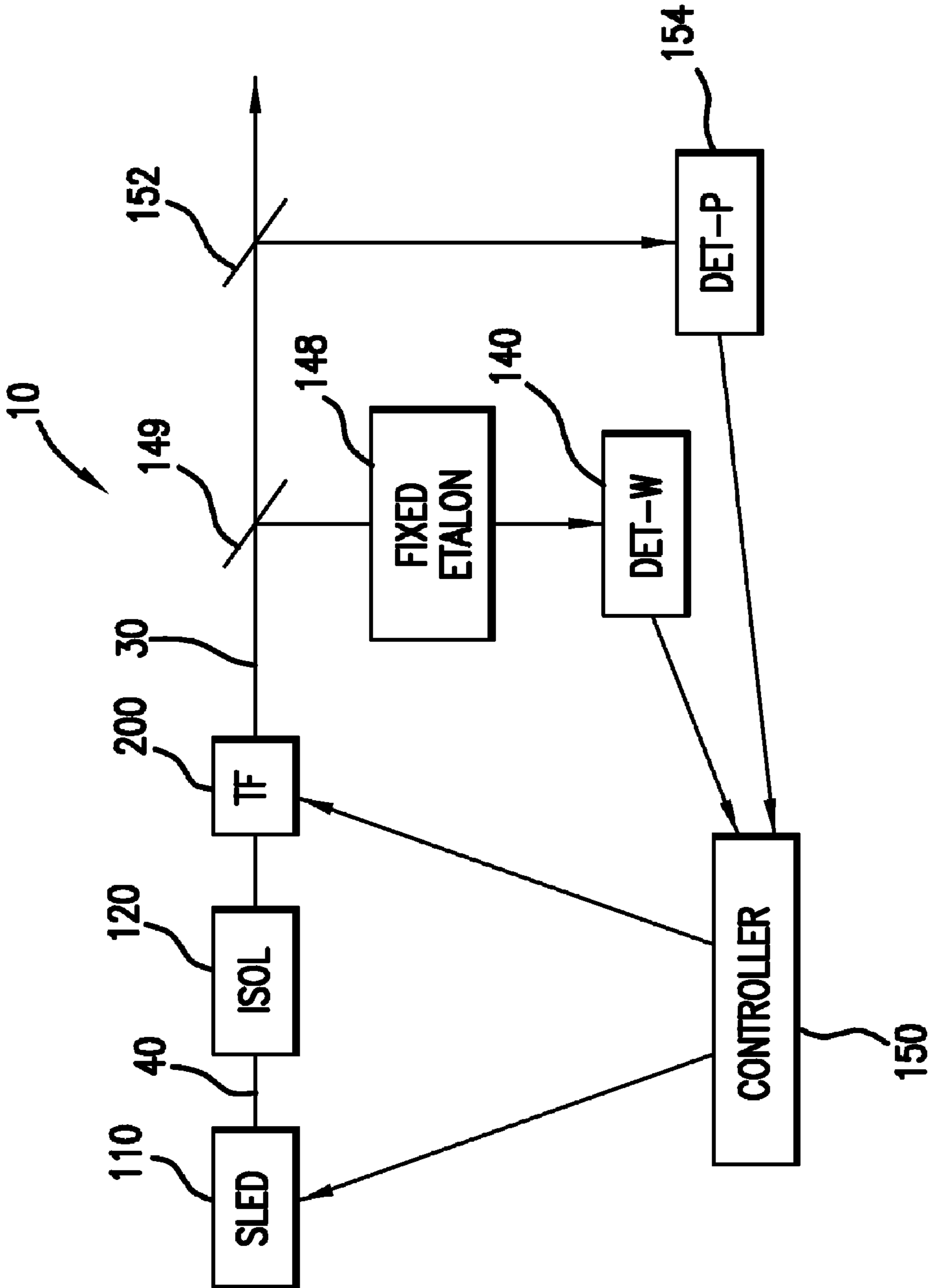


FIG. 6

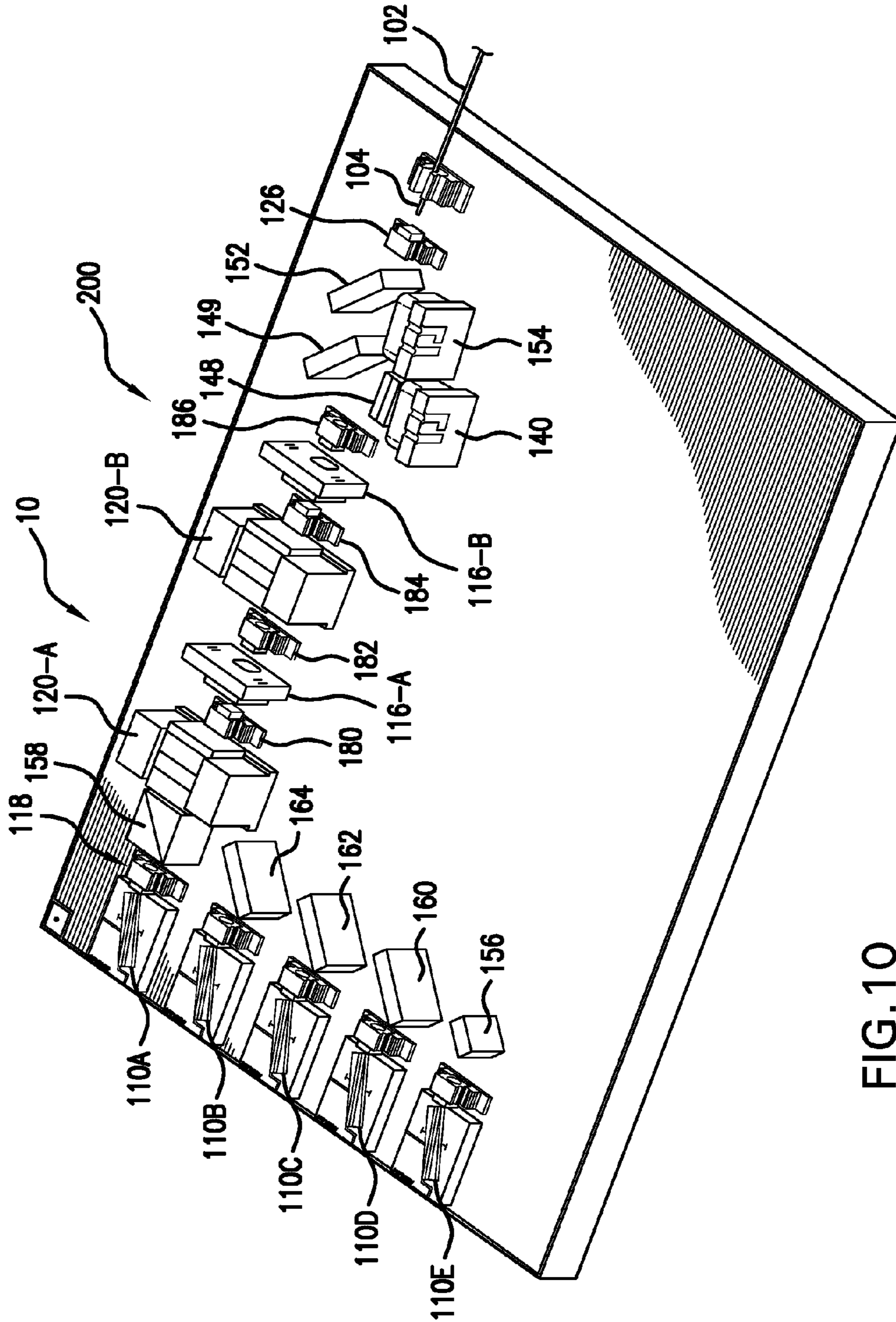


FIG. 10

F-P TRANSMISSION, $L_c=5.5(6.3) \mu\text{m}$, FINESSE=500(200), $m=7$, (BW~55/1.82 GHz/cm-1)

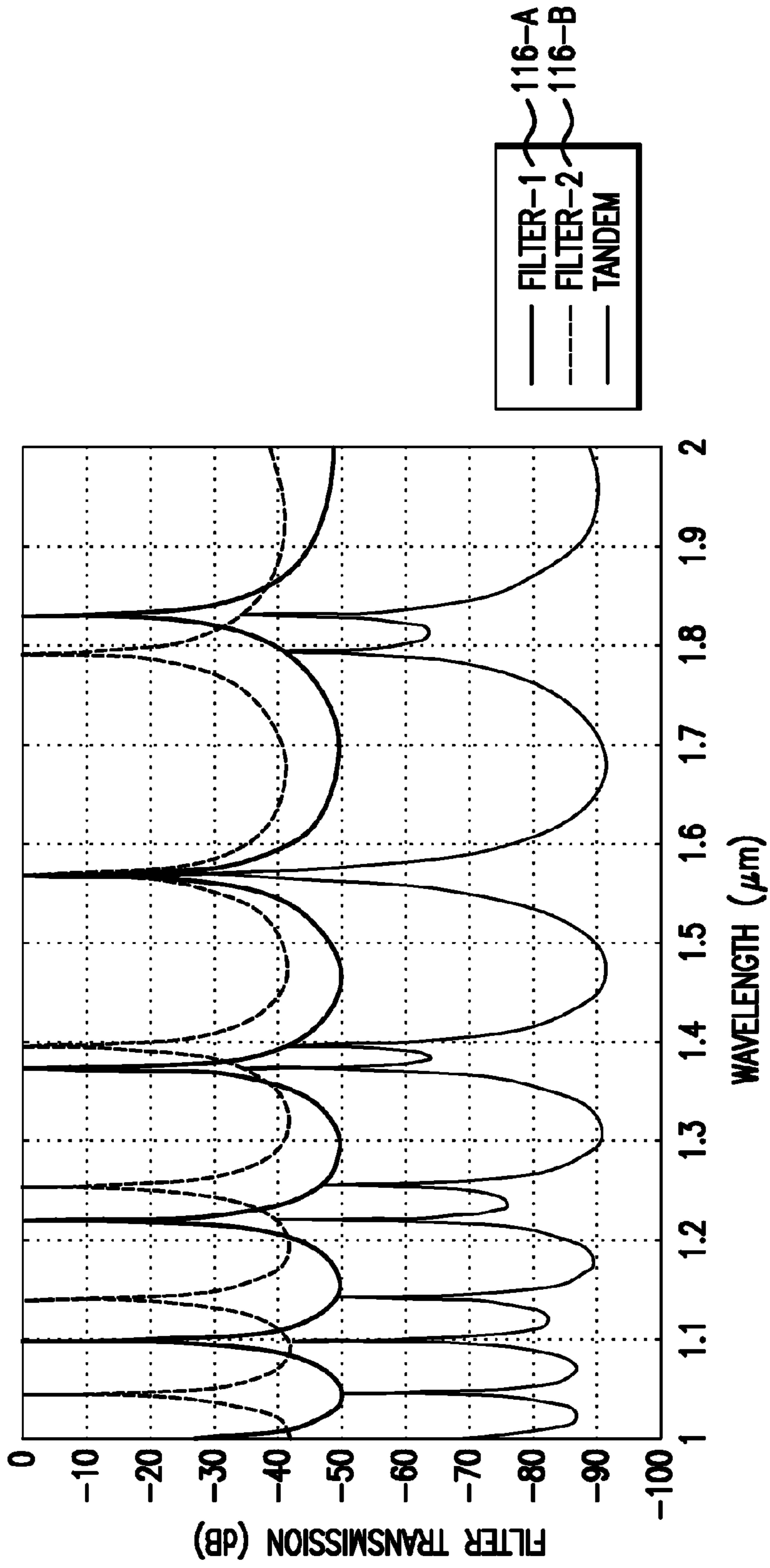


FIG.11

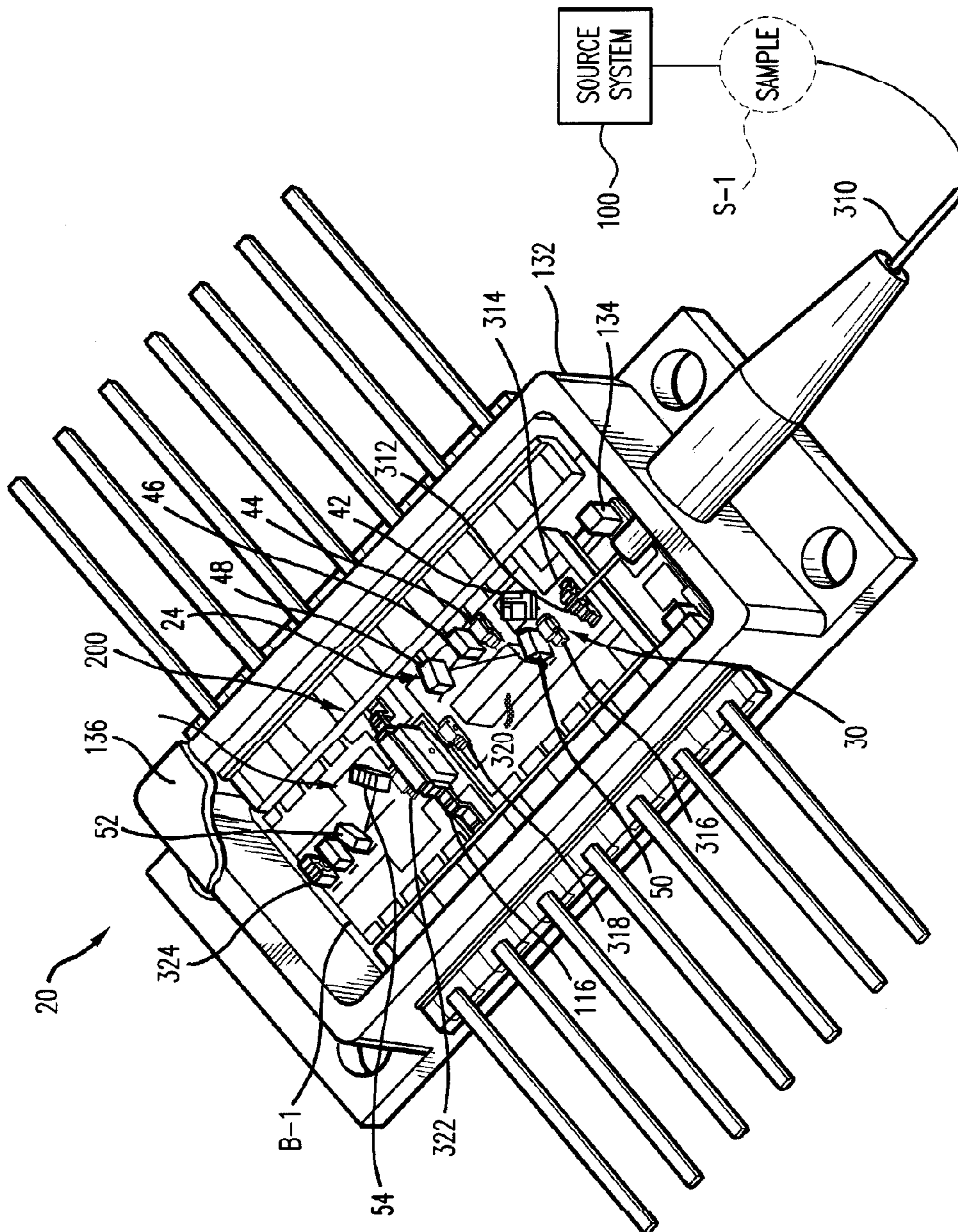


FIG. 12A

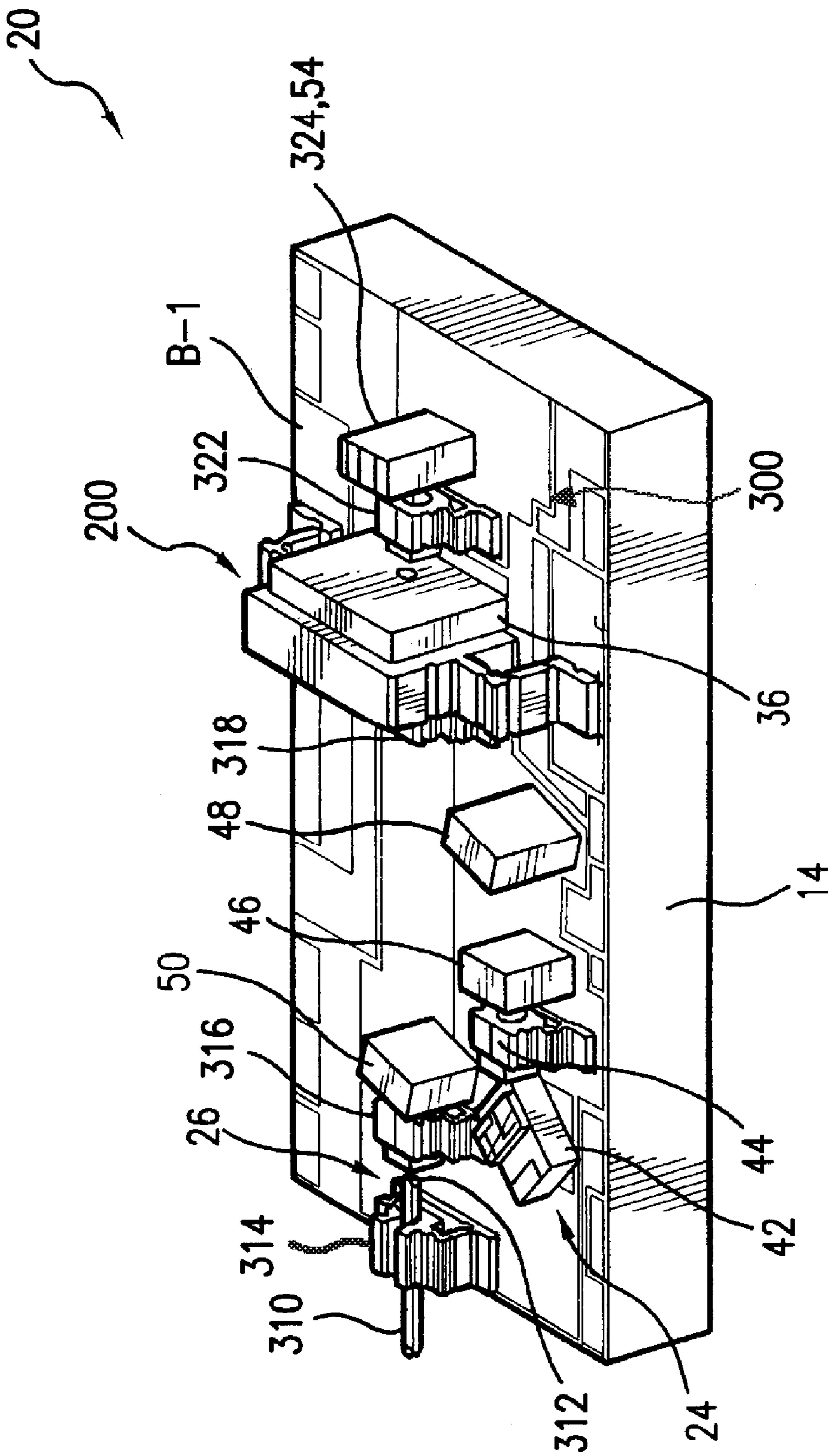


FIG. 12B

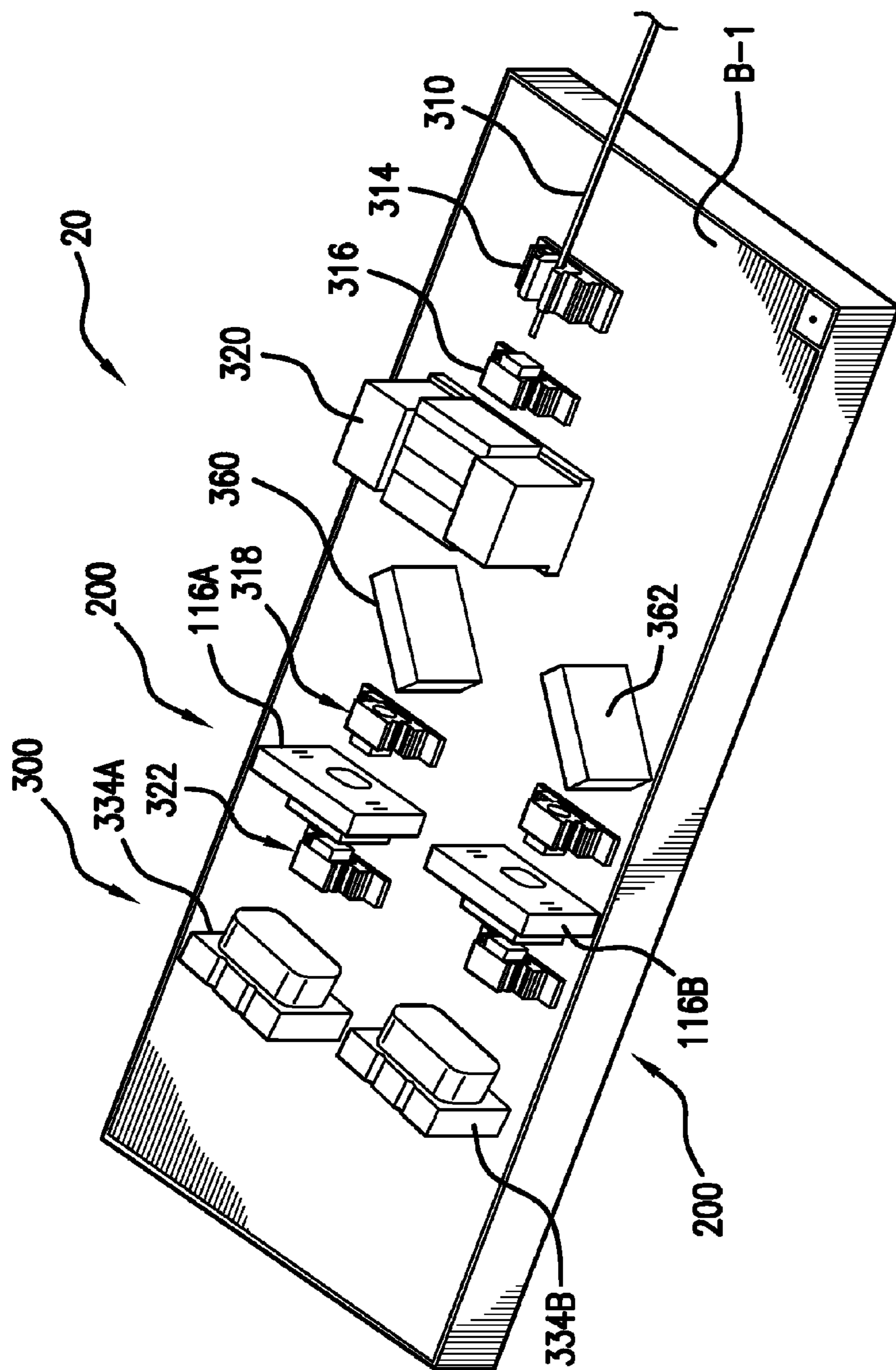


FIG. 13

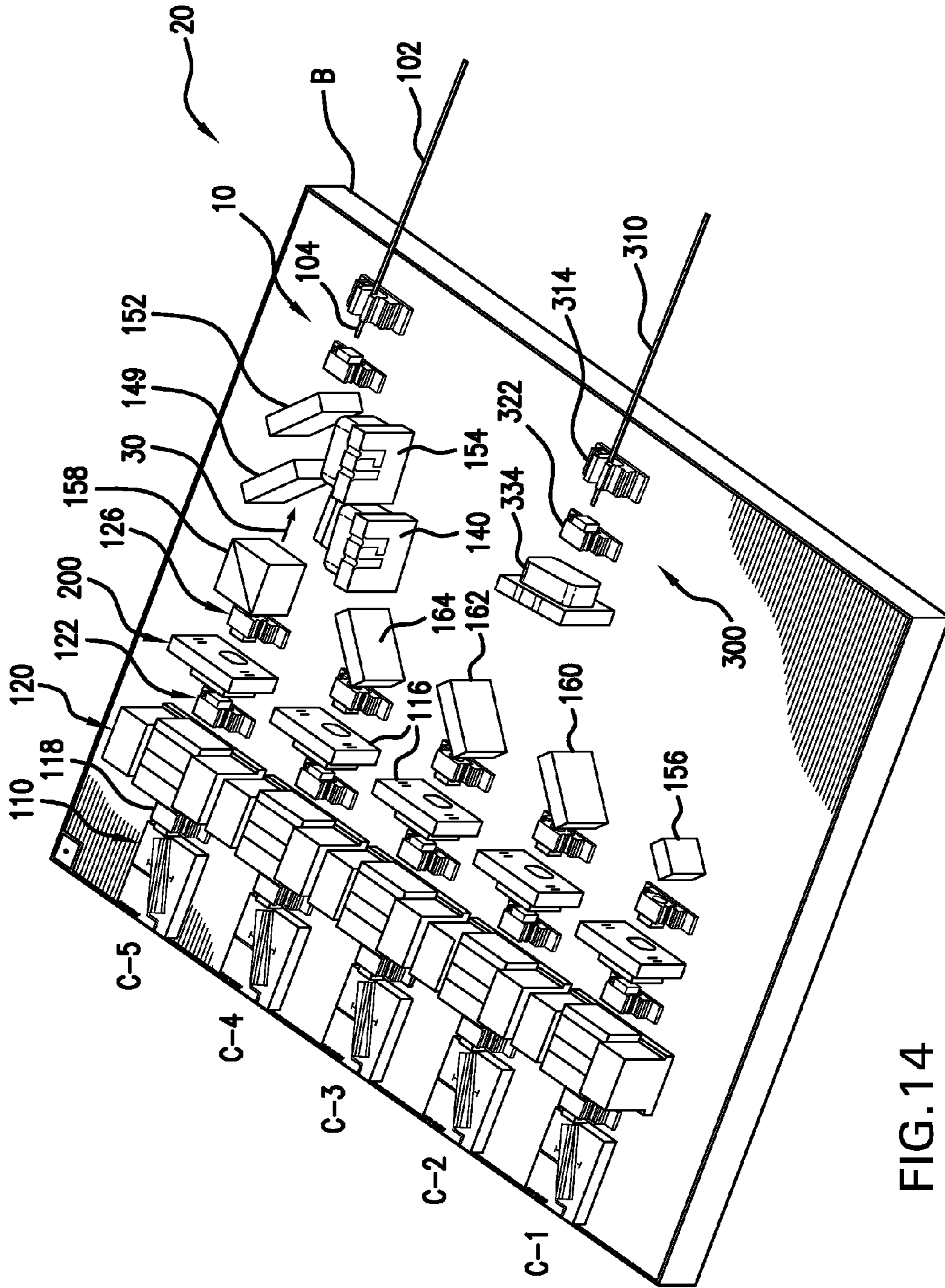


FIG. 14

INTEGRATED SPECTROSCOPY SYSTEM

Matter enclosed in heavy brackets [] appears in the original patent but forms no part of this reissue specification; matter printed in italics indicates the additions made by reissue.

RELATED APPLICATIONS

This application is a Division of U.S. application Ser. No. 10/688,690 filed on Oct. 17, 2003 now U.S. Pat. No. 7,061,618, which is incorporated herein by reference in its entirety.

BACKGROUND OF THE INVENTION

Minimally, optical spectroscopy systems typically comprise a source for illuminating a target, such as a material sample, and a detector for detecting the light from the target. Further, some mechanism is required that enables the resolution of the spectrum of the light from target. This functionality is typically provided by a spectrally dispersive element.

One strategy uses a combination of a broadband source, detector array, and grating dispersive element. The broadband source illuminates the target in the spectral scan band, and the signal from the target is spatially dispersed using the grating, and then detected by an array of detectors.

The use of the grating, however, requires that the spectroscopy system designer make tradeoffs. In order to increase the spectral resolution of these systems, aperturing has to be applied to the light provided to the grating. As more spectral resolution is required, more light is required to be rejected by the narrowing spatial filter. This problem makes this strategy inappropriate for applications requiring a high degree of spectral precision combined with sensitivity.

Another approach is to use a tunable narrowband source and a simple detector. A typical approach relies on a tunable laser, which is scanned over the scan band. By monitoring the magnitude of the tunable laser's signal at the detector, the spectrum of the sample is resolved. These systems have typically been complex and often had limited wavelength scanning ranges, however.

Still another approach uses light emitting diodes (LEDs) and an acousto-optic modulator (AOM) tunable filter. One specific example combines multiple light emitting diodes (LEDs) in an array, each LED operating at a different wavelength. This yields a relatively uniform spectrum over a relatively large scan band. The light from the diodes is then sent through the AOM tunable filter, in order to create the tunable optical signal.

The advantage of this system is the use of the robust LED array. This provides advantages over previous systems that used other broadband sources, such as incandescent lamps, which had limited operating lifetimes and high power consumption.

While representing an advance over the previous technology, the disadvantages associated with this prior art system were related to the use of the AOMs, which are relatively large devices with concomitantly large power consumptions. Moreover, AOMs can also be highly temperature sensitive and prone to resonances that distort or alter the spectral behavior, since they combine a crystal with a radio frequency source, which establishes the standing wave in the crystal material to effect the spectral filtering.

Grating-based spectrometers also tend to be large devices. The device packages must accommodate the spatially dispersed signal from the sample. Further, the interface between

the grating and the detector array must also be highly mechanically stable. Moreover, these grating based systems can be expensive because of costs associated with the detector arrays or slow if mechanical scanning of the detector or grating is used.

SUMMARY OF THE INVENTION

The drawbacks associated with the prior art spectrometers arise from the large size of the devices combined with the high cost to manufacture these devices combined with poor mechanical stability. These factors limit the deployment of spectrometers to applications that can justify the investment required to purchase these devices and further accommodate their physical size.

Accordingly, the present invention is directed to an integrated spectrometer system. Specifically, it is directed to the integration of a tunable Fabry-Perot system with a source system and/or detector system. The use of the Fabry-Perot filter system allows for a high performance, low cost device. The integration of the filter system with the source system and/or detector system results in a device with a small footprint. Further, in the preferred embodiment, the filter system is based on microelectromechanical systems (MEMS), which yield a highly mechanically robust system.

In general, according to one aspect, the invention features a spectroscopy system. The system comprises a source system for generating light to illuminate a target, such as a fiber grating or a material sample. A tunable Fabry-Perot filter system is provided for filtering light generated by the source. A detector system is provided for detecting light filtered by the tunable filter from the target. According to the invention, at least two of the source system, tunable Fabry-Perot filter system, and the detector system are integrated together.

Specifically, in one embodiment, the source system and tunable Fabry-Perot system are integrated together on a common substrate, such as an optical bench, also sometimes called a submount. In another embodiment, the tunable Fabry-Perot filter system and the detector system are integrated together on a common substrate, such as an optical bench. Finally, in still another implementation, all three of the source system, tunable Fabry-Perot filter system, and the detector system are integrated together on a common bench, and possibly even in a common hermetic package.

Temperature control is preferably provided for the system. Currently this is provided by a heater, which holds the temperature of the system above an ambient temperature, or a thermoelectric cooler. For example, the thermoelectric cooler is located between the bench and the package to control the temperature of the source system, tunable Fabry-Perot filter system, and/or the detector system. As a result, a single cooler is used to control the temperature of the filter and SLED chip, lowering power consumption, decreasing size, while increasing stability.

In the preferred embodiment, the source system comprises a broadband source. This can be implemented using multiple, spectrally multiplexed diode chips. Preferably, superluminescent light-emitting diodes (SLEDs) are used. These devices have a number of advantages relative to other sources, such as incandescent sources. Specifically, they have better spectral brightness, longer operating lifetimes, and a smaller form factor.

In order to increase the spectral accuracy of the system, a tap can also be used to direct a part of the tunable signal to a detector. A spectral reference, such as a fixed etalon with multiple spectral transmission peaks is placed between the detector and the tap, in order to create a fringe pattern on the

detector during the scan, thereby enabling monitoring of the wavelength of the tunable signal. An optical power tap can also be included to monitor the real time emitted optical power during the scan.

The tunable Fabry-Perot filter system comprises single or multiple filters. In one example, multiple serial filters are used. In another embodiment, multiple parallel filters are used.

In still further embodiments, multiple detectors can be used. These detectors can be responsive to different wavelengths or a calibration signal.

In the preferred embodiment, in order to make the system small, compact and highly robust, a micro-electro-mechanical system (MEMS) Fabry-Perot tunable filter is used. These devices can achieve high spectral resolutions in a very small footprint.

Finally, in the preferred embodiment, isolation is provided between the source system and the tunable Fabry-Perot filter system. This prevents back reflections from the filter into the source system that can disturb the operation of the source system. In one example, an isolator is installed on the optical bench between the SLED and the tunable filter. A quarter wave plate can also be used. This rotates the polarization of the returning light so that it is not amplified by the highly polarization anisotropic SLED gain medium. In another embodiment, the isolation is provided on the bench, with the tunable Fabry-Perot filter system and the detector system.

The present invention is also directed to an integrated tunable source that combines a broadband source and a tunable filter, such as a tunable Fabry-Perot filter, although other tunable filters could be used in this configuration. Applications for this device extend beyond spectroscopy.

Between the tunable filter and the light source, isolation is preferably provided. This stops back reflections from the tunable filter into the diode, which could impact its performance. Isolation can be achieved using a number of techniques. In one embodiment, a discrete isolator is used. In another embodiment, when a SLED is used as the source, a quarterwave plate is used between the SLED chip and the filter. Finally, a flat-flat cavity Fabry-Perot tunable filter is used in still another embodiment, with isolation being accomplished by tilting the filter relative to the SLED.

A variety of other light sources can be used, including LEDs, doped fiber or waveguide amplified spontaneous emission sources, and thermal sources.

According to still another aspect, the invention features a high power tunable source. This addresses one of the primary drawbacks associated with the use of a broadband source and tunable filter configuration, namely their usually low output power. Specifically, an optical amplifier is further added in order to increase the power of the tunable signal. As a result, power levels comparable to those attainable with tunable lasers can be achieved in this configuration.

In a typical implementation, the amplifier is a semiconductor optical amplifier (SOA). In other examples, various types of fiber amplifiers are used, however.

The above and other features of the invention including various novel details of construction and combinations of parts, and other advantages, will now be more particularly described with reference to the accompanying drawings and pointed out in the claims. It will be understood that the particular method and device embodying the invention are shown by way of illustration and not as a limitation of the invention. The principles and features of this invention may be employed in various and numerous embodiments without departing from the scope of the invention.

The above and other features of the invention including various novel details of construction and combinations of parts, and other advantages, will now be more particularly described with reference to the accompanying drawings and pointed out in the claims. It will be understood that the particular method and device embodying the invention are shown by way of illustration and not as a limitation of the invention. The principles and features of this invention may be employed in various and numerous embodiments without departing from the scope of the invention.

BRIEF DESCRIPTION OF THE DRAWINGS

In the accompanying drawings, reference characters refer to the same parts throughout the different views. The drawings are not necessarily to scale; emphasis has instead been placed upon illustrating the principles of the invention. Of the drawings:

FIGS. 1A and 1B illustrate embodiments of the integrated spectroscopy system according to the present invention;

FIG. 2 is a perspective view showing a tunable source, according to the present invention, and including a detector system for detecting the tunable signal from the sample;

FIG. 3A is a perspective view of the MEMS Fabry Perot tunable filter, used in embodiments of the present invention, which is compatible with tombstone mounting on the optical bench;

FIG. 3B is an exploded view of the inventive Fabry Perot tunable filter;

FIG. 4 is a perspective view showing an amplified tunable source, according to the present invention, in a hermetic package;

FIG. 5 is a perspective view showing a reference detector embodiment of a tunable source, according to the present invention, in a hermetic package;

FIG. 6 is a block diagram of an embodiment of the tunable source with both a wavelength and power reference detector;

FIG. 7 is a perspective view showing still another embodiment of a tunable source, according to the present invention, using two SLED chips;

FIG. 8 is a perspective view showing a further embodiment of a tunable source, according to the present invention using multiple SLED chips and tunable filters;

FIG. 9 is a perspective view showing another embodiment of a tunable source, according to the present invention, using parallel filters and multiple SLED sources;

FIG. 10 is a perspective view showing a further embodiment of a tunable source, according to the present invention, using serial filters;

FIG. 11 is a plot of wavelength as a function of transmission showing the relationship between the free spectral ranges of the serial filters, in one embodiment;

FIG. 12A is a perspective view of a tunable detector spectroscopy system, according to the present invention;

FIG. 12B is a perspective view of another embodiment of a tunable detector spectroscopy system, according to the present invention;

FIG. 13 is a perspective view of still another embodiment of a tunable detector spectroscopy system, according to the present invention, using multiple parallel filters; and

FIGS. 14 and 15 show two fully integrated spectroscopy systems in which a tunable source and a detector system are integrated on the same bench.

DETAILED DESCRIPTION OF THE PREFERRED EMBODIMENTS

FIGS. 1A and 1B illustrate an integrated spectroscopy system 1, which has been constructed according to the principles of the present invention.

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Specifically, FIG. 1A shows two alternative integration configurations.

According to configuration 1, a source system 100 is provided. This is a broadband source, which generates light 40 for illuminating a target, such as sample S-1 or a fiber grating, for example. This target selectively absorbs and/or scatters the light from the source system 100. The transmitted light is then received by a tunable Fabry-Perot filter system 200. This functions as a narrow band tunable spectral filter. It tunes its passband over the scan band within the spectral band of the source system 100. As a result, it resolves the spectrum of the target S-1 into a time response. This time-resolved signal is then detected by detector system 300.

According to the integration provided by this configuration 1, the tunable Fabry-Perot filter system 200 and the detector system 300 are integrated together. Specifically, in the preferred embodiment, the tunable Fabry-Perot filter system 200 and the detector system 300 are installed on a common bench B-1. Moreover, in the current embodiment, the tunable Fabry-Perot filter system 200 and the detector system 300 are integrated together on the common bench B-1 in a common hermetic package.

The integration of the Fabry-Perot filter system 200, with the detector system 300 on the common bench B-1, yields the tunable detector 20 which is characteristic of the configuration 1 integration.

FIG. 1A also illustrates a second configuration, configuration 2 integration. In this second configuration, the source system 100 and the tunable Fabry-Perot system 200 are integrated together. In the preferred embodiment, they are installed together on a common bench B-2. Further, in the current implementation, the source system 100 and the tunable Fabry-Perot filter system are integrated together on the common bench B-2 and installed in a common hermetic package to yield a tunable source 10. This tunable source 10 generates a tunable signal 30, which is used to illuminate a target, located in this second configuration at position S-2. The target either scatters or absorbs spectral components of the tunable signal as it is scanned across the scan band. This allows the detector system 300 to resolve the time varying signal as the spectral response of the target S-2.

FIG. 1B illustrates a fully integrated system according to still another embodiment. Here, the source system 100, the tunable Fabry-Perot filter system 200, and the detector system 300 are integrated together. Specifically, in the preferred embodiment, they are integrated together and installed on a common bench B. This bench B is preferably located in a hermetic package.

Depending on whether the tunable source system 100, the Fabry-Perot filter system 200, and detector system 300, are combined as a tunable source 10 or tunable detector 20, the target is located either in position S-1 or S-2. Specifically, in the implementation of a tunable source 10 with the source system 100 and the tunable Fabry-Perot filter system 200 functioning to create a tunable signal, the tunable signal 30 is coupled outside of the hermetic package and off of the bench B to the target S-2, in the case of configuration 2. Alternatively, if the tunable Fabry-Perot filter system 200 and the detector system 300 function to yield the tunable detector 20, then the broadband signal 40 from the source system 100 is coupled off of the bench and the outside of the hermetic package to the target S-1 in the case of the first configuration.

FIG. 2 illustrates a first embodiment of the tunable source 10. Specifically, in this embodiment, the bench B-2 holds the tunable Fabry-Perot filter system 200 and the source system 100 on a common planar surface. The generated tunable signal 30 is coupled off of the bench B-2 by an optical fiber

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102. In the preferred embodiment, this optical fiber 102 is a single transverse mode fiber. This has advantages in that it renders the tunable signal 30 very stable, even in the event of mechanical shock to the single mode fiber 102.

The source system 100 is implemented using, in this embodiment, a superluminescent light emitting diode (SLED) 110. The diode 110 is installed on a submount 112. The submount 112 is, in turn, installed on the bench B-2. In the preferred embodiment, the SLED chip 110 is solder bonded to the submount 112, which further includes metallizations 114 to facilitate wire bonding to provide electrical power to the SLED chip 110. Further, the submount 112 is solder bonded to the bench B-2, which in turn, has metallizations 115 to enable formation of the solder bonds.

These SLEDs are relatively new, commercially-available devices and are sold by Covega Corporation, for example, (product numbers SLED 1003, 1005, 1006). These devices are currently available in wavelength ranges from 1,200 nanometers (nm) to 1,700 nm from a variety of vendors. They are waveguide chip devices with long gain mediums similar to semiconductor optical amplifiers. An important characteristic is their high spectral brightness.

The broadband signal 40 that is generated by the SLED chip is collimated by a first lens component 114. This lens component 114 comprises a lens substrate 117, which is mounted onto a deformable mounting structure 118. The deformable mounting structure is preferably as those structures described in U.S. Pat. No. 6,559,464 B1 to Flanders, et al., which is incorporated herein in its entirety by this reference. The alignment structure system allows for post installation alignment by mechanical deformation of the mounting structure 118 of the lens substrate 117.

The collimated light from the first lens component 114 in the preferred embodiment is coupled through an isolation system, such as an isolator 120 or quarterwave plate. The beam from the isolator is then collimated by a second lens element 122 and coupled into the Fabry-Perot tunable filter system 200. The isolator system prevents all back reflections or back reflections that have a polarization that is aligned with the gain polarization of the SLED chip 110. These reflections arise from the Fabry-Perot filter system 200. This isolation promotes the stability in the operation of the SLED chip 110.

In the preferred embodiment, the tunable filter system 200 is implemented as a MEMS tunable Fabry-Perot filter 116. This allows for single transverse mode spectral filtering of the broadband light 40 from the SLED chip 110, yielding the tunable signal 30. Tunable signal 30 is coupled into the endface 104 of the single mode optical fiber 102. In the current embodiment, the endface 104 of the optical fiber 102 is held in alignment with the MEMS tunable filter 116, via a fiber mounting structure 106. Again, this allows for post installation alignment of the fiber endface 104 to maximize coupling of the tunable signal 30, into the single mode fiber 102. The fiber 102 transmits the tunable signal 30 to target S-2 and then, the response is detected by detector system 300.

Depending on the embodiment, the Fabry-Perot filter 116 has either a curved-flat cavity or a flat-flat cavity. The curved flat cavity increases angular tolerance between the two mirrors of the Fabry-Perot filter. The flat-flat cavity provides better single mode operation. Moreover, there is the option to avoid the necessity for discrete isolators or waveplates by angle isolating the filter for the source system 100.

FIG. 3A is a close up view of the tunable filter 116. The tunable filter 116 comprises a MEMS die 410. This has a number of wire bond locations 412 for making electrical connection to the MEMS die 410. A MEMS die 410 provides the moveable mirror portion or component of the tunable

filter. A fixed mirror portion or component **414** is bonded to the MEMS die **410** in order to define the Fabry Perot cavity. In one embodiment, the fixed mirror component provides the flat mirror and the MEMS die **410** provides the curved mirror.

In the preferred embodiment, the tunable filter **116** is “tombstone” mounted onto the bench B, B-1, B-2. Specifically, the fixed mirror substrate **414** extends down below the bottom of the MEMS die **416** by a distance L. Specifically, the fixed mirror substrate has a bottom surface **418** that serves as a foot that is bonded to the bench. Preferably, a layer of solder **420** is used to attach the fixed mirror substrate **414** to the bench B. In the preferred embodiment, the distance L is approximately 1-10 micrometers.

FIG. 3B is an exploded view of the tunable filter **116**. This shows the fixed mirror substrate **414** disconnected from the MEMS die **410**. Flexures **421** define a MEMS membrane **423**. The deflectable membrane **423** holds the mirror layer **424** of the tunable mirror and covers a depression **425** formed in the membrane **423** that forms the curved mirror of one embodiment. Metallization pads **426** are provided on the MEMS die **410** in order to solder attach the fixed mirror substrate **414** to the MEMS die **410**.

The general construction of this tunable filter is described in, for example, U.S. patent application Ser. No. 09/734,420, filed on Dec. 11, 2000 (now Publication No. U.S. 2002-0018385). This application is incorporated herein, in its entirety by this reference.

FIG. 4 illustrates another embodiment of the tunable source **10**. In this embodiment, the broadband signal generated by the SLED chip **110** is again coupled through a first lens component **114** to an isolator **120**. A second lens component **122** is further provided for coupling the broadband signal into the filter **116** of the Fabry-Perot filter system **200**.

Then, a third lens component **126** is provided to couple the tunable optical signal **30** into a semiconductor optical amplifier **128**. In the preferred embodiment, this semiconductor optical amplifier chip **128** is installed on an amplifier sub-mount **130**, which is installed on the bench B-2. The amplified tunable optical signal generated by the semiconductor optical amplifier chip **128** is then coupled into the endface **104** of the optical fiber **102** to be coupled out of the hermetic package **132**. This allows the tunable signal **30** to be coupled, in an amplified state, to the target S-2 followed by detection by the detector system **300**.

In some other embodiments additional isolators are located between the fiber endface **104** and the amplifier chip **128** and between the amplifier chip **128** and the third lens component **126**.

In the preferred embodiment, the hermetic package **132** is a standard telecommunications hermetic package. Specifically, it comprises a standard butterfly package. The lid **136** is shown cut away to illustrate the internal components. Further, the optical bench B-2 is preferably installed on a thermoelectric cooler **134**, which enables a controlled environmental temperature to stabilize the operation of the SLED chip **110** and the tunable Fabry-Perot filter system **200**.

Electrical leads **138** are further provided to transmit electrical signals to the pads **146** on the inside of the hermetic package **132**. Wire bond are made between pads **146** and the active components such as the SLED chip **110**, MEMS tunable filter **116**, and SOA **128**.

The FIG. 4 embodiment has the advantage that the tunable signal **30** received from the tunable Fabry-Perot filter system **200** is amplified to further increase the dynamic range and the signal-to-noise ratio of the spectroscopy system.

In the embodiment of FIG. 5, the tunable source **10** also combines a SLED chip **110**, a first lens component **114**,

isolator **120**, and a second lens component **122**. This launches the broadband signal **40** from the SLED chip into the tunable filter system **200**. A third lens component **126** is further provided. This collimates the beam. A splitter, however, comprising a partially reflective substrate **149**, provides a portion of the tunable signal **30** to a detector **140**. This detector **140** can be used to monitor the magnitude or power in the tunable signal **30**. In another embodiment, a reference substrate **148** is installed between the detector **140** and the tap **149**. This reference substrate **148** provides stable spectral features. In one embodiment, this is provided by a fixed etalon substrate. A controller monitoring the output of the detector **140** compares the tunable signal to the spectral features of the reference substrate **148** to thereby resolve the instantaneous wavelength of the tunable signal **30**.

In still other embodiments, instead of a reference substrate, a gas cell is used as the spectral reference for calibrating the scan of the tunable filter **116**. Also two splitters can be included to provide simultaneous spectral and power references.

The tunable signal, which is not coupled to the detector **140** by the tap **149** is launched by a fourth lens component **147** into the fiber endface **104** of the optical fiber **102**.

FIG. 6 illustrates the general operation provided by a controller **150** of the tunable source **10**. Specifically, the controller **150** is used to control the power or current supplied to the SLED chip **110**. Its broadband signal **40** is coupled to the isolator **120**. The controller also controls the tunable pass band of the tunable filter system **200** to generate the tunable signal **30**.

In the case of monitoring the frequency of the tunable signal, a first tap **149** couples a portion of the tunable signal to a spectral reference **148**, which in the illustrated embodiment, is a fixed etalon. This allows the detector **140** to detect the wavelength of the tunable signal **30** during the scan.

In the preferred embodiment, a power detector **154** is also provided. This is added to the optical train using second tap **152**, which again couples the portion of the tunable signal **30** to a power detector **154**. The controller **150** controls and monitors the wavelength detector **140** and the power detector **154** to determine both the wavelength and the power in the tunable signal **30**.

FIG. 7 illustrates another embodiment of the tunable source **10**. This embodiment is used either to increase the power or the spectral width of the scan band of the tunable source **10**. Specifically, multiple SLED chips, and specifically two SLED chips **110A** and **110B**, are installed together on the optical bench B-2. In the illustrated embodiment, the SLED chips **110A** and **110B** are installed on a common sub-mount **112**, which is in turn, bonded to the bench B-2.

Two first lens components **118A**, **118B** are provided to couple the broadband signals from their respective SLED chips **110A**, **110B** and collimate those beams. A combination of a fold mirror **156** and a combiner **158** are provided to combine the broadband signals from each of these SLED chips **110A**, **110B** into a single broadband signal, which is coupled through the isolator **120**.

The beam from the isolator **120** is then focused by a second lens component **122** into the tunable filter **200**. A third lens component **126** then couples the tunable signal into the optical fiber **102** via the endface **104**.

In the high power version of the FIG. 7 embodiment, a polarization rotator, such as a quarterwave plate **160** is provided in the beam path of one of the SLED chips **110A**, **110B**. In the illustrated embodiment, this polarization rotator **160** is provided in the beam path of the second SLED chip **110**. This rotates the polarization of the light from the second SLED

chip **110B** by 90° . Then, the combiner **158** is a polarization combiner that is transmissive to the polarization of the light from the first SLED chip **110A**, but reflective to the polarization of light from the second SLED chip **110B**. As a result, the beams from each of the SLED chips **110A**, **110B** are merged into a common broadband signal with increased power.

In a second implementation of the FIG. 7 embodiment, the SLED chips **110A**, **110B** operate at different spectral bands. Specifically, SLED chip **110A** generates light in a scan band A and SLED chip **110B** generates light in an adjacent but different scan band B. The combiner **158** is a wavelength division multiplex combiner that is configured to be transmissive to the band of light generated by the SLED chip **110A**, but reflective to light in the band generated by SLED chip **110B**. As a result, the combined signal generated together by the SLED chip **110A**, **110B** has a broader scanband than could be generated by each of the SLED chips individually. This allows for increased bandwidth in the tunable signal **30** that is generated by the tunable source **10**.

FIG. 8 illustrates another embodiment of the tunable source **10**. This embodiment uses a tunable filter system **200**, which includes an array of tunable filters **116** and broadband light sources in order to increase the spectral width of the scanband. Typically, and in the illustrated embodiment, an array of five SLED chips **110** are mounted in common on the bench **B-2**. The light from each of these SLED chips **110** is collimated by respective first lens components **118**. Specifically, there is a separate lens component **118** for each of these SLED chips **110**. Separate isolators **120** are then provided for the broadband signals from each of the SLED chips **110**.

An array of second lens components **122** is further provided to couple the broadband signal into an array of tunable filters **200**. Specifically, separate Fabry-Perot tunable filters **116** are used to filter the signal from each of the respective SLED chips **110**. Finally, an array of third lens components **126** is used to re-collimate the beam from the tunable Fabry-Perot filters **116** of the tunable filter system **200**.

For channel **1**, **C-1**, a fold mirror **156** is used to redirect the beam from the SLED chip **110**. The WDM filter **160** is used to combine the broadband signal from the SLED chip **110** of channel **C-2** with the signal from channel **C-1**. Specifically, the filter **160** is reflective to the wavelength range generated by the SLED chip **110** of channel **C-2**, but transmissive to the wavelength range of light generated by the SLED chip **110** of channel **C-1**.

In a similar vein, WDM filter **162** is reflective to the signal band generated by the SLED chip **110** of channel **C-3**, but transmissive to the bands generated by SLED chips **110** of channels **C-1** and **C-2**. WDM filter **164** is reflective to the light generated by SLED chip **110** of channel **C-4**, but transmissive to the bands generated by the SLED chips **110** of channels **C-1**, **C-2**, and **C-3**. Finally, WDM filter **158** is reflective to all of the SLED chips, but the SLED chip **110** of channel **C-5**. As a result, the light from the array of SLED chips is combined into a single broad band tunable signal **30**.

A first tap **149** is provided to reflect a portion of the light through the etalon **148** to be detected by the wavelength detector **140**. Then, another portion is reflected by tap **152** to the power detector **154**. The remaining tunable signal is coupled by the fourth lens component **106** into the optical fiber **102** via the endface **104**.

The FIG. 8 embodiment can operate according to a number of different modes via a controller **150**. Specifically, in one example, only one of the SLED chips in channels **C-1** to **C-5** is operating at any given moment in time. As a result, the tunable signal **30** has only a single spectral peak. The full scan band is achieved by sequentially energizing the SLED chip of

each channel **C-1** to **C-5**. This tunable signal is scanned over the entire scan band covered by the SLED chips of channels **C-1** to **C-5** turning on the SLED chips in series, or sequentially.

In another mode, each of the SLED chips is operated simultaneously. As a result, the tunable signal has spectral peaks in each of the scan bands, covered by each of the SLED chips **110** simultaneously. This system results in a more complex detector system **300**, which must demultiplex the separate scan bands from each of the SLED chips **110** from each of the channels at the detector. Specifically, in one embodiment, five (5) detectors are used with a front-end wavelength demultiplexor.

FIG. 9 shows an embodiment of the tunable source **10** that has both increased power and increased scanning range over a single SLED. It comprises two subcomponents, which are configured as illustrated in FIG. 7 embodiment. Specifically, each channel **C-1**, **C-2** has two SLED chips **110A**, **110B** that are polarization combined. The output is isolated by an isolator **120** and then filtered by a tunable filter **116** for each channel **C-1**, **C-2**. The signals from the two channels are then wavelength multiplexed using a combination of a fold mirror **170** and a dichroic or WDM filter **172**. Specifically, the dichroic mirror **172** is transmissive to the scan band of the SLED chips **110A**, **110B** of channel **C-1**, but reflective to the SLED chips **110A**, **110B** of channel **C-2**.

In order to improve the manufacturing yield of the FIG. 9 embodiment, in one implementation, each of the channels **C-1** and **C-2** are fabricated on separate sub-benches **SB-1** and **SB-2**. The sub-benches **SB-1**, **SB-2** are then bonded to each other or to a common bench in order to yield the FIG. 9 embodiment.

FIG. 10 illustrates still another embodiment, which covers a wide spectral band. Specifically, it includes five SLED chips **110A** to **110E**. A series of first lens optical components **118** are used to collimate the beams from each of the SLED chips **110A-110E**. In the present embodiment, the SLED chips **110A** to **110E**, each operate over different spectral bands. They are then wavelength combined using a combination of fold mirrors and filters **156**, **160**, **162**, **164** and **158**, as discussed with reference to the FIG. 8 embodiment.

The FIG. 10 embodiment further includes, preferably, two isolators **120A**, **120B**. These isolate respective tunable filters **116A**, **116B**. Lens components **180**, **182**, **184**, and **186** are used to couple the optical signal generated by the SLEDs **110A-110E**, through the first tunable filter **116A** and the second tunable filter **116B** of the tunable filter system **200**, and then, through the wavelength tap **149** and the power tap **152** to the endface **104** of the optical fiber **102**.

The use of the five SLED chips **110** increases the effective scan band of the tunable source **10**. In the preferred embodiment, the tandem tunable filters have free spectral ranges FSR as illustrated in FIG. 11.

Specifically, filter **1** **116A**, and filter **2** **116B** have different free spectral ranges. As a result, they function in a vernier configuration. This addresses limitations in the free spectral range of the tunable filters individually.

Typically, if a single tunable filter was used, its free spectral range would have to be at least as wide as the total scan band of the broad band signals generated by the sources. In the illustrated embodiment, the tunable filters are combined to increase the free spectral range of the tunable filter system, since the peak transmissivity, through both tunable filters **116A-116B**, only arises at wavelengths where the passbands of the two filters **116A-116B** are coincident.

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FIGS. 12A and 12B show tunable detector systems 20, to which the principles of the present invention are also applicable.

Specifically, with reference to FIG. 12A, the tunable detector system generally comprises a package 132 and an optical bench B-1, which is sometimes referred to as a submount. The bench B-1 is installed in the package 132, and specifically on a thermoelectric (TE) cooler 134, which is located between the bench B-1 and the package 132, in the specific illustrated embodiment.

The package 132, in this illustrated example, is a butterfly package. The package's lid 136 is shown cut-away in the illustration.

The tunable detector optical system, which is installed on the top surface of the bench B-1, generally comprises the detector system 300, the tunable filter system 200, and an optional reference source system 24.

In more detail, the optical signal from the target S-1 to be monitored is transmitted to the system via a fiber pigtail 310, in the illustrated example. This pigtail 310 terminates at an endface 312 that is secured above the bench B-1 using a fiber mounting structure 314 in the illustrated implementation. The optical signal passes through a first lens optical component 316, which collimates the beam to pass through an isolator 320. A second lens optical component 318 launches the optical signal into the tunable filter system 200. A MEMS implementation of the tunable filter is shown. The filtered signal passes through a third lens optical component 322 and is then detected by an optical signal detector 324.

In the illustrated implementation, each of the lens and tunable filter optical components comprises the optical element and a mounting structure that is used to secure the optical element to the bench, while enabling most installation alignment.

Turning to the path of the optical reference, the emission from a reference light source 42, such as a broadband source, e.g., a SLED, passes through reference lens optical component 44 to a fixed filter 46, which, in the present implementation, is a fixed etalon. It converts the broadband spectrum of the SLED 42 into a series of spectral peaks, corresponding to the various orders of the etalon transmission, thereby producing the stable spectral features of the optical reference.

The optical reference is then reflected by fold mirror 48 to a dichroic or WDM filter 50, which is tuned to be reflective at the wavelength of the optical reference, but transmissive within the band of the optical signal. Thus, the optical reference is similarly directed to the optical filter system 200.

At the detector system 20, a dichroic filter 52 reflects the optical reference to a reference detector 54.

FIG. 12B shows an operationally similar tunable optical filter system 20, for the purposes of the present invention. Reference numerals have been used for functionally equivalent parts. The differential between the two designs lies in the design of the detector system 300. This second embodiment utilizes only a single detector 324, 54 that detects both the optical reference and the optical signal. In this illustration, the package is not shown for clarity.

FIG. 13 shows another embodiment of the tunable detector 20. The signal from the target is transmitted to the detector 20 via fiber 310. A first lens component 316 collimates the light from the fiber. Second lens components 318 couple the light into the tunable filters 116A, 116B of the filter system 200. Third lens components 322 focus the light to the detector system 300.

This version uses two tunable filters 116A, 116B, each filtering a portion of the scan band. Corresponding detectors 334A, 334B detect the transmitted signal from each filter.

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The spectrum is divided into two subbands by WDM filter 360, which reflects half of the spectral scan band to the second filter 116B via fold mirror 362. The other half of the spectrum is transmitted through the WDM filter 360 to tunable filter 116A.

FIG. 14 shows a single bench fully integrated system according to still another embodiment. It generally operates as described relative to the FIG. 8 embodiment. Specifically, it uses a series of SLEDs in five channels, yielding a tunable source 10, to generate a wide band tunable signal 30. The detector system 300 is integrated on the same bench B and the tunable source. Specifically, light returning from the target in fiber 310 is coupled to detector 334 using lens component 322.

FIG. 15 shows another single bench fully integrated system according to still another embodiment. Here, the light to and from the target is carried in the same fiber 102, 310. The tap substrate 152 is used to direct outgoing light 30 to the power detector 154 and light returning from the target to the detector 334.

While this invention has been particularly shown and described with references to preferred embodiments thereof, it will be understood by those skilled in the art that various changes in form and details may be made therein without departing from the scope of the invention encompassed by the appended claims.

What is claimed is:

1. A tunable light source spectroscopy system, comprising:
 - a superluminescent light emitting diode for generating broadband light; and
 - a tunable Fabry Perot filter for spectrally filtering the broadband light from the broadband source to generate a tunable signal;
 - an optical fiber for carrying the tunable signal to irradiate a sample;
 - a detector for detecting a response of the sample to the tunable signal to determine a spectroscopic response of the sample; and
 - an isolator interposed between the superluminescent light emitting diode and the tunable filter for preventing back reflections from the tunable filter into the superluminescent light emitting diode.
2. A tunable light source spectroscopy system as claimed in claim 1, wherein the superluminescent light emitting diode and the Fabry Perot filter are installed in common on an optical bench.
3. A tunable light source spectroscopy system as claimed in claim 1, wherein the superluminescent light emitting diode, isolator, and tunable filter are integrated on a common optical bench.
4. A tunable light source spectroscopy system as claimed in claim 1, comprising an amplifier for amplifying the tunable signal.
5. A tunable light source spectroscopy system, comprising:
 - a superluminescent light emitting diode for generating broadband light; and
 - a tunable Fabry Perot filter for spectrally filtering the broadband light from the broadband source to generate a tunable signal;
 - an optical fiber for carrying the tunable signal to irradiate a sample;
 - a detector for detecting a response of the sample to the tunable signal to determine a spectroscopic response of the sample; and
 - an amplifier for amplifying the tunable signal, wherein the amplifier is a semiconductor optical amplifier.

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6. A tunable light source spectroscopy system as claimed in claim 5, further comprising an isolator interposed between the superluminescent light emitting diode and the tunable filter for preventing back reflections from the tunable filter into the broadband source.

7. A tunable light source spectroscopy system, comprising: a superluminescent light emitting diode for generating broadband light; and

a tunable Fabry Perot filter for spectrally filtering the broadband light from the broadband source to generate a tunable signal;

an optical fiber for carrying the tunable signal to irradiate a sample;

a detector for detecting a response of the sample to the tunable signal to determine a spectroscopic response of the sample; and

an amplifier for amplifying the tunable signal, wherein the amplifier is a fiber amplifier.

8. A tunable light source spectroscopy system as claimed in claim 7, wherein the fiber amplifier is one of an erbium, ytterbium, thulium or Raman fiber amplifier.

9. A tandem filtered amplified spontaneous emission (ASE) scanning optical source, comprising:

an ASE source for generating broadband light in a spectral band;

a first tunable Fabry Perot filter having a first passband that is tuned over a scanband in the spectral band of the ASE source for filtering the broadband light;

an isolation system between the ASE source and the first tunable Fabry Perot filter for preventing back reflections from the tunable first Fabry Perot filter into the ASE source;

a second tunable Fabry Perot filter having a second passband that is tuned over a scanband in the spectral band of the ASE source for filtering light from the first tunable Fabry Perot filter; and

a second isolation system between the first tunable Fabry Perot filter and the second tunable Fabry Perot filter;

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wherein the first tunable Fabry Perot filter and the second tunable Fabry Perot filter form a filter system that has a peak transmissivity to the broadband light where the first passband and the second passband are coincident.

10. A source as claimed in claim 9, wherein the first tunable Fabry Perot filter and the second tunable Fabry Perot have different free spectral ranges.

11. A source as claimed in claim 9, wherein the isolation system is an isolator.

12. A source as claimed in claim 9, wherein the isolation system is a quarterwave plate.

13. A source as claimed in claim 9, wherein the ASE source is a superluminescent light emitting diode.

14. A source as claimed in claim 9, wherein the first and second tunable Fabry-Perot filters are MEMS tunable Fabry-Perot filters.

15. A source as claimed in claim 9, further comprising an optical bench, the ASE source, first tunable Fabry Perot filter, and second tunable Fabry Perot filter being integrated together on the optical bench.

16. A source as claimed in claim 9, further comprising a reference detector for detecting part of a tunable optical signal from the filter system and a spectral reference for generating a fringe pattern on the detector during scanning of the tunable optical signal.

17. A source as claimed in claim 9, further comprising two or more broadband sources for generating broadband light that is converted into a tunable optical signal by the first tunable Fabry Perot filter and the second tunable Fabry Perot filter.

18. A source as claimed in claim 9, further comprising lenses for collecting the broadband light emitted from the ASE source and coupling the broadband light into the first tunable Fabry Perot filter and for collecting a tunable optical signal from the first tunable Fabry Perot filter and coupling the tunable optical signal into the second tunable Fabry Perot filter.

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